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5	330	rout\$4 near10 per adj second\$1 and @ad<20010403	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/07 11:37
6	154	server\$1 near10 per adj second\$1 and @ad<20010403	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/07 12:08
7	1655	(process processes) near10 per adj second\$1 and @ad<20010403	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/07 12:09
8	43	(process processes) near10 per adj second\$1 and @ad<20010403 and 709/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/07 12:09
-	2	6160989.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/07 11:15

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